

Notice of References Cited	Application/Control No. 10/675,348	Applicant(s)/Patent Under Reexamination WATANABE ET AL.	
	Examiner John Wahnkyo Lee	Art Unit 2624	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-3,444,378 A	05-1969	SCHUSTER RONALD; et. al.	250/363.01
*	B	US-4,780,613 A	10-1988	Berstein et al.	250/343
*	C	US-5,033,015 A	07-1991	Zwirn, Robert	702/116
*	D	US-5,902,417 A	05-1999	Lillington et al.	136/246
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	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Nagasawa et al., "Application of Fourier Transform Infrared Emission Spectrometry to Surface Analysis," March/April 1984, Vol. 38, 168-173
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.